

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/674,432	MADHAVAN ET AL.
	Examiner	Art Unit
	Olabode Akintola	3691
		Page 1 of 1

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*	B	US-7,016,872	03-2006	Bettis et al.	705/36R
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	M	US-			

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**NON-PATENT DOCUMENTS**

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	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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